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Application/Control No.	Applicant(s)/Patent under Reexamination
10/711,790	LEE ET AL.
Examiner	Art Unit
Dao H. Nguyen	2818

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST (USPAT; USPG-PUB; EPO; JPO; IBM-TDB; USOCAR)	4/4/2007	DN
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